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| Substitute Form PTO-1449<br>(Modified)   | U.S. Department of Commerce<br>Patent and Trademark Office | Attorney's Docket No.<br>12732-158001 | Application No. <u>10/603949</u><br><del>New Application</del> |
| <b>Information Disclosure Statement<br/>by Applicant</b><br>(Use several sheets if necessary)<br>(37 CFR §1.98(b)) |  | Applicant<br>Shigeharu Monoe          |  |
|  |  | Filing Date<br>June 26, 2003          | Group Art Unit<br><u>2823</u>                                  |

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| Examiner Initial      | Desig. ID | Document Number    | Publication Date | Patentee        | Class | Subclass | Filing Date If Appropriate |
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| Examiner Initial  | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation |    |
|   |           |                 |                  |                          |       |          | Yes         | No |
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| Examiner Signature<br>  | Date Considered<br><u>8/20/04</u> |
| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. |                                   |